Semiconductor Device(100TQFP) Dehumidifying Property

1. Purpose:
The graphic shows semiconductor device dehumidifying property.
2. Device:
The device is called 100TQFP.
3. Experiment
The experiment is divided by two steps.(Humidifying and Dehumidifying)
Before you read the graphic, You need to know what is the Absorption Ration?

First step:(Humidifying)
When we do any experiment, We must set one point as 0.0Wt%. Under the experiment.

Test Condition:
A: Baking process performed on the device of 100TQFP for 120□-60 hours, counted as 0.0Wt%.
B: Humidifying experiment
Humidifying Condition of 33□-87% for 168 hours, the volume weight weighing at daily basis, to check absorption ration of: Wt%.

In fact, The humidifying experiment is a preceding term.

Maybe you will ask why we let the humidifying condition of 33□-87% for168 hours.
The reason that the condition was the best that we can arrive at that time. If we can, we also can set the condition of 98%RH, 33.

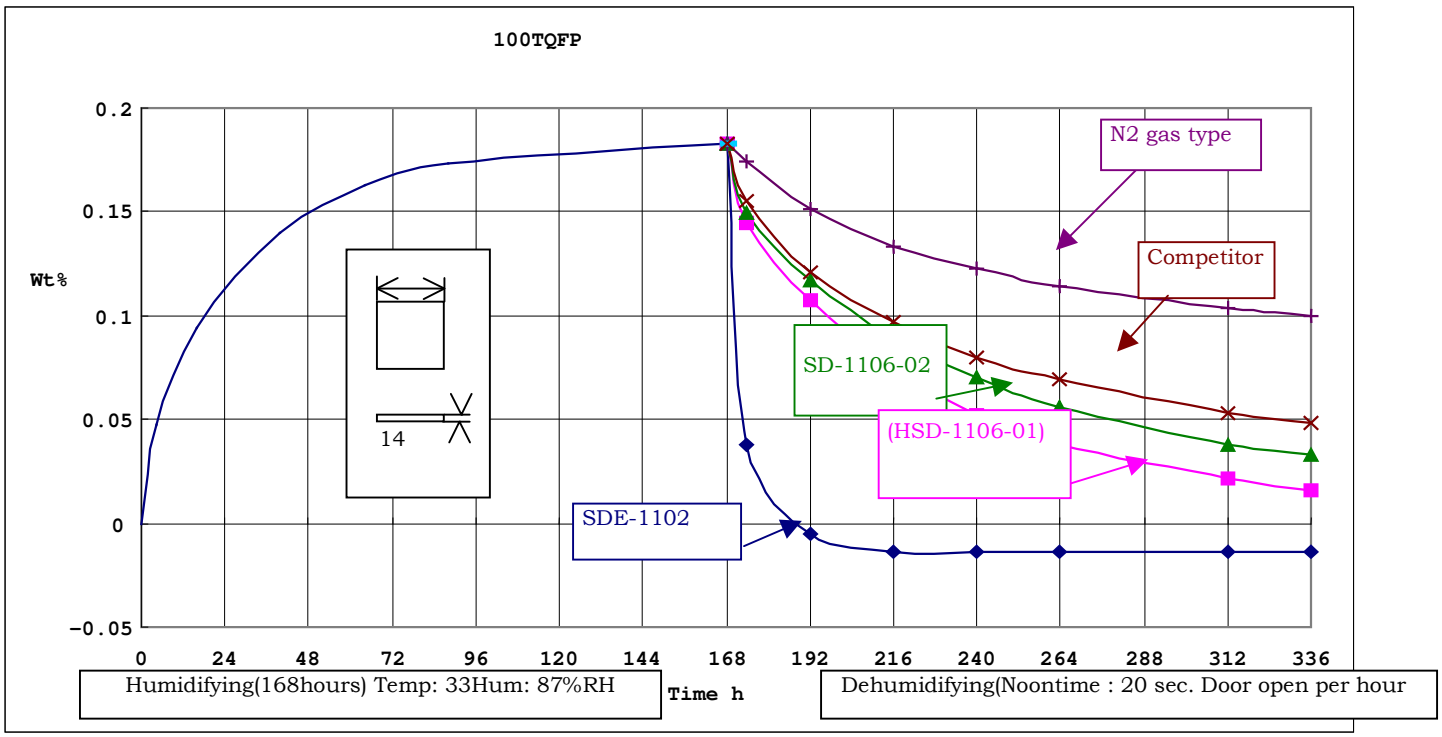
The purpose to set the condition to let humidity in device saturately.

Second Step(dehumidifying)
Then, We moves device with humidity to our cabinets to check their absorption performances.

Test Condition:

C. The openings of the cabinet door: 20 second by every hour per day for continuous 7 days, the volume weight will be weighed every day for getting absorption ratio of wt%.

D: Using our HSD-1106-01,SD-1106-02, SDE-1002
Setting points for HSD-1106-01: 1%RH, 25.
Setting points for SD-1106-02: 2%RH, 25.
Setting points for SDE-1002: 3%RH, 60.



Conclusion:
Different from the general baking system, Due to no heating stress on the devices at all, no defective products can be observed in use of cabinets.

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